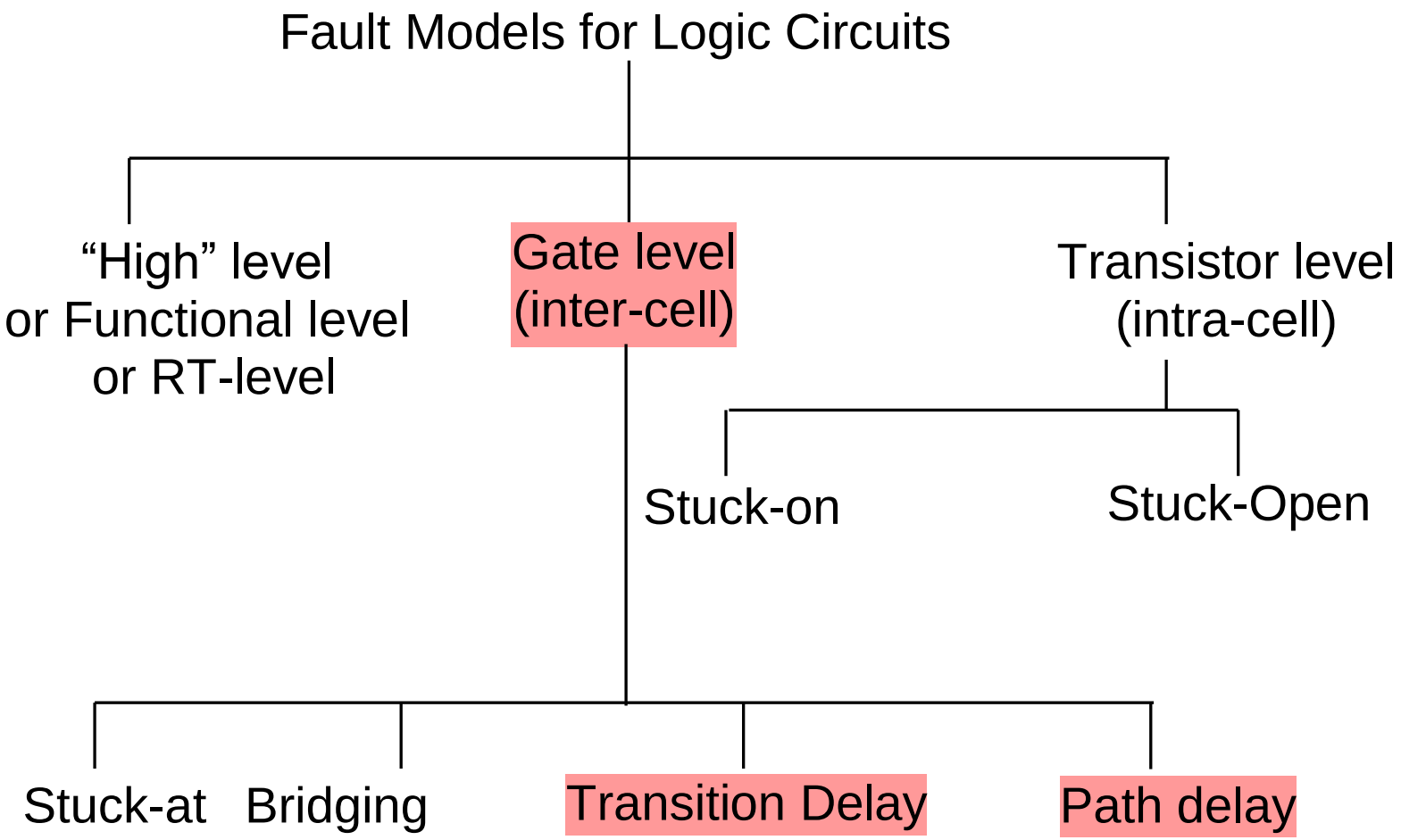
Fault Modeling

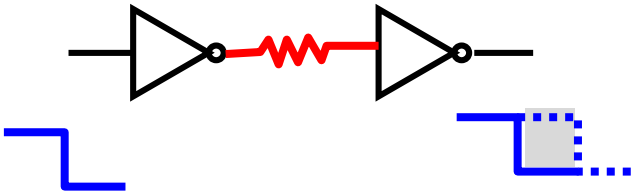
- Introduction
- **Fault Models**
  - Stuck-at fault (1961)
  - Bridging fault (1973)
  - **Delay fault (1974)**
    - **Path delay fault (PDF)**
    - **Transition delay fault (TDF)**
  - Transistor level fault
- Fault Detection
- Fault Coverage
- Conclusion

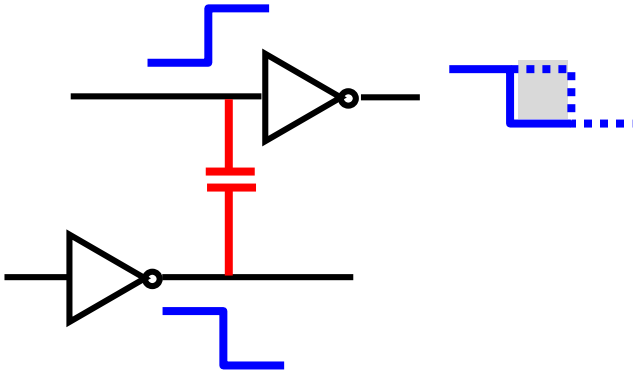
Classification of Fault Models



Some Defects Are Not Stuck-at

- Some defects change circuit **timing** but not function
  - ① **Random defects**: Resistive opens, resistive bridging,
  - ② **Systematic defects**: crosstalk, process variation in V_t



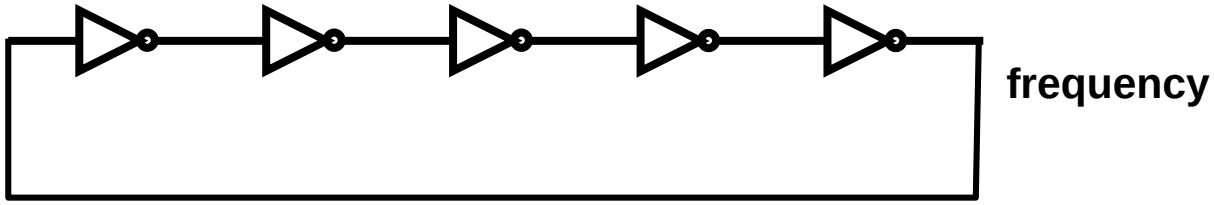


- *Delay fault* cause a circuit [Breuer 74]
  - fails to operate correctly at **specified speed**
  - but produces correct output at **slower speed**

Delay Fault Models Are Needed

How to Detect Delay Faults?

- **Two categories**
  - ① **Global delay fault: affects large area of circuit**
    - **Example: Wrong doping → V_t shift**
    - **Can be detected by *on-chip process monitors***

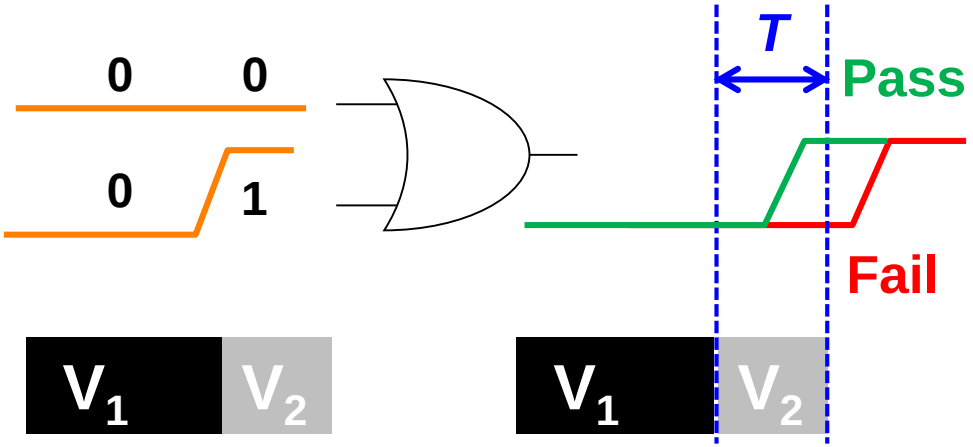


  - ② **Local delay fault: affects small area of circuit**
    - **Poor contact/via → resistive open**
    - **Can be detected by *delay testing***

Delay Testing Detects Delay Faults

What Patterns for Delay Test?

- Delay faults needs *two-pattern test*
  - As opposed to *one-pattern test* for stuck-at faults
- A two-pattern test consists of a pair of test patterns (test vectors)
  - V_1: initialize circuit state
  - V_2: *launch* transition, *propagate fault effect* to output
- Control timing (T) between V_1 and V_2 carefully



Delay Faults Require 2-pattern Test

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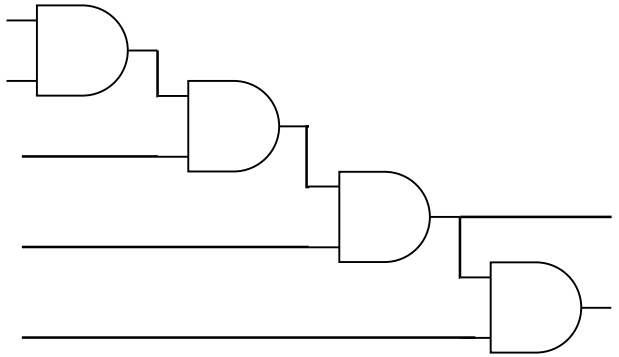
Two Delay Fault Models

- *Path Delay Fault, PDF* [Smith 85]
  - Path delay of the faulty path > clock period
- *Transition (Delay) Fault, TDF* [Barzilai 83] [Levendel 86]
  - Path delay of all paths through the faulty node > clock period

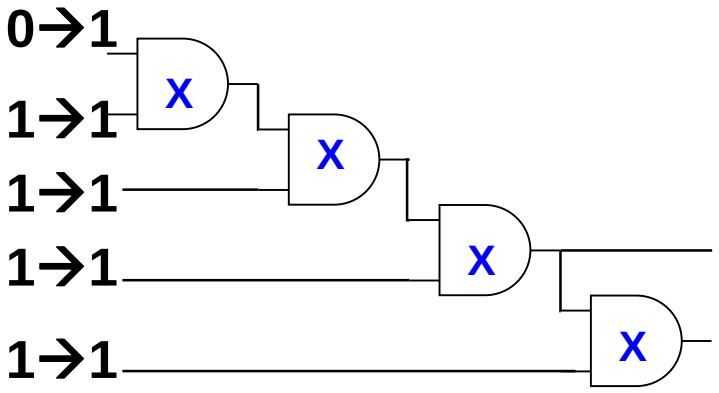
- Other delay fault models
  - Gate delay fault [Iyengar 88]
  - Segment delay fault [Heragu 96]
  - …



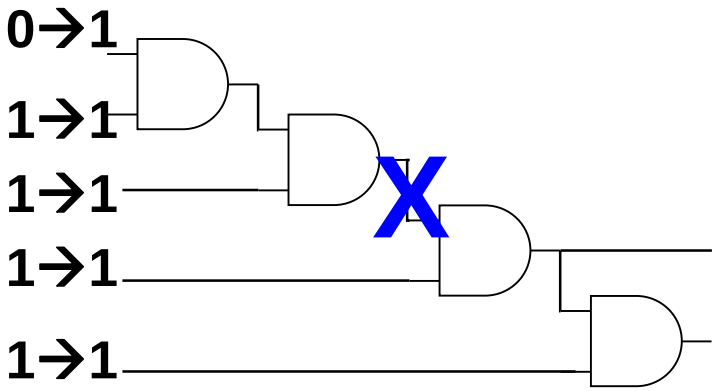
Trade off Model Complexity and Accuracy

Example

- Clock period = 10.0ns
  - good gate delay = 2.0ns
- PDF (fault distributed along path)
  - 3.0 +2.6 +2.7 = 8.3 < 10 → pass
  - 3.0 +2.6 +2.7 +2.9 = 11.2 > 10 → fail



- TDF (lumped fault = 9.0 ns)
  - 2.0+2.0+2.0+9.0=15.0 → fail
  - 2.0+2.0+2.0+9.0+2.0 = 17.0 → fail

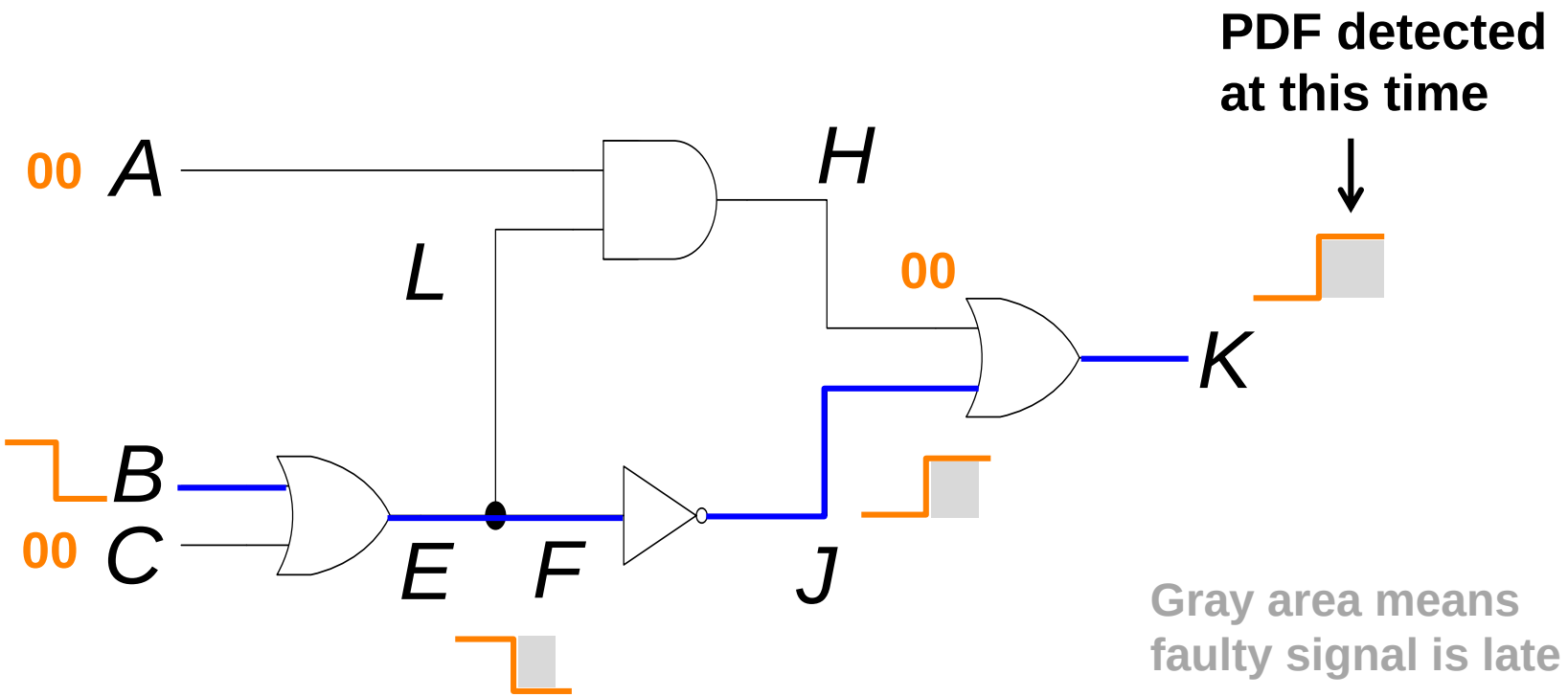


Faulty size=$delay_{faulty}$ - $delay_{good}$

PDF		TDF
Distributed		Lumped
Small fault size	⟷	Large fault size

Path Delay Fault (PDF)

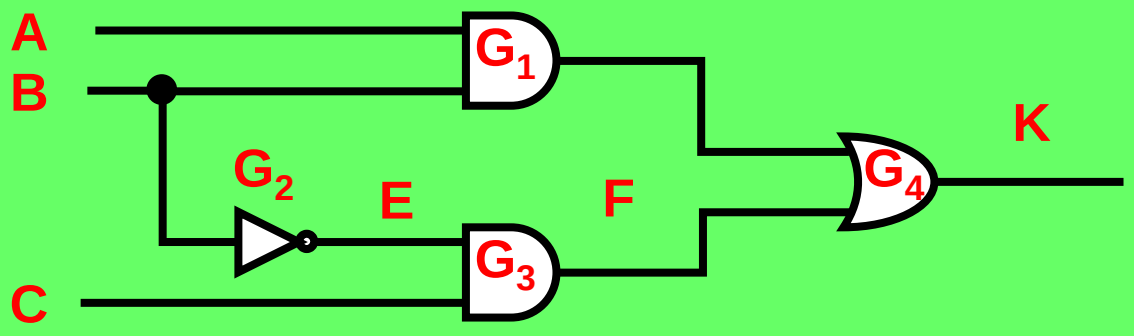
- For each path, two polarity: falling ↓ , rising ↑ (at PI)
- Example:
  - 5 paths: {AHK, BELHK, BEFJK, CELHK, CEFJK}
  - 10 path delay faults
  - Two-pattern test for PDF ↓BEFJK



Quiz

Q1: How many path delay faults in this circuit?
A:

Q2: Does ABC=001→011 detect ↑BEFK fault?
A:



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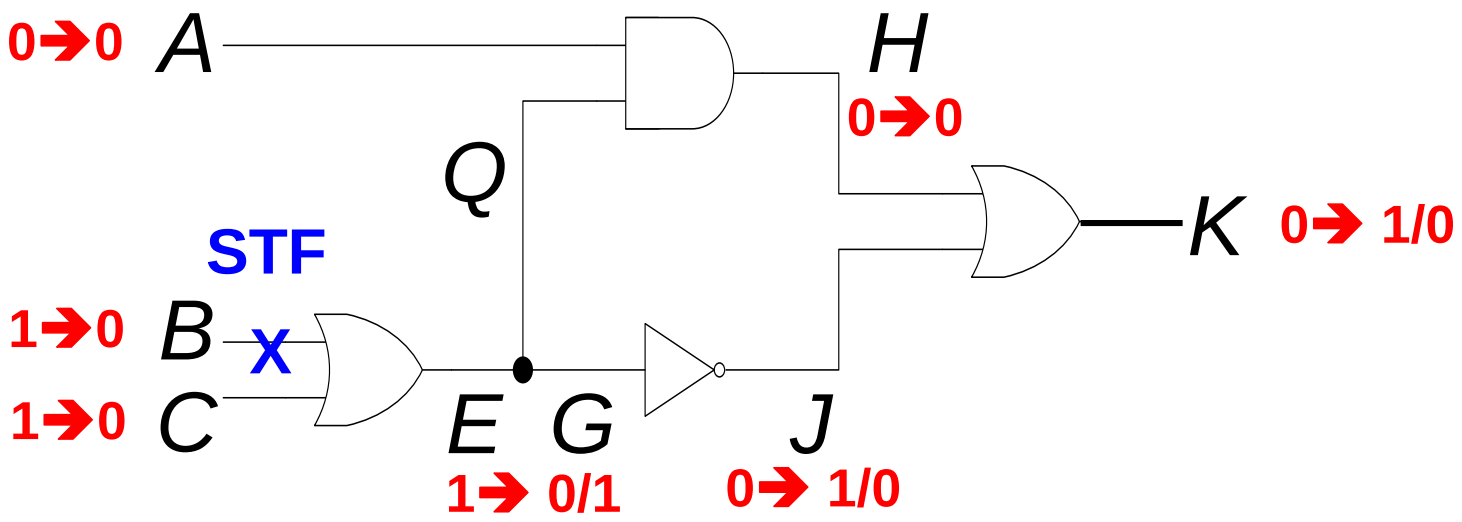
Transition Delay Fault (TDF)

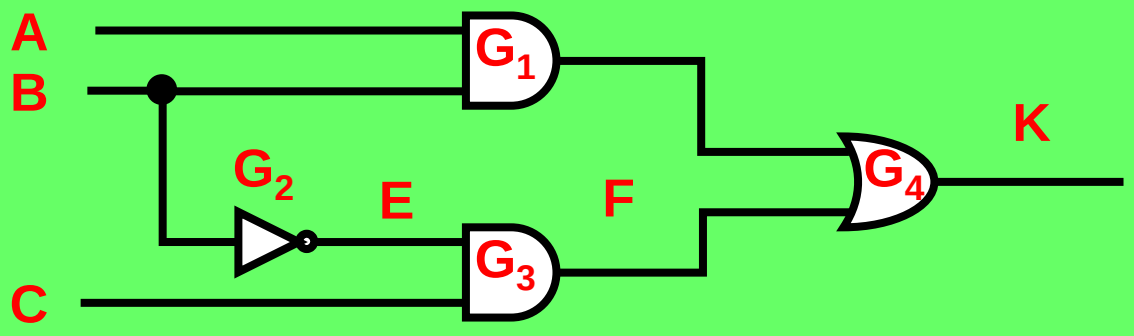
- Each node has 2 TDF: *slow-to-rise (STR)*, *slow-to-fall (STF)*
- Two-pattern test for TDF
  - V_1: Initialization pattern: control initial value at fault site
    - 0 for STR fault, 1 for STF fault
  - V_2: launch transition and propagate fault effect to output
    - Detect SA0 for STR fault , SA1 for STF fault
- Example: total 9 nodes, 18 TDF
  - *B* STF fault detected



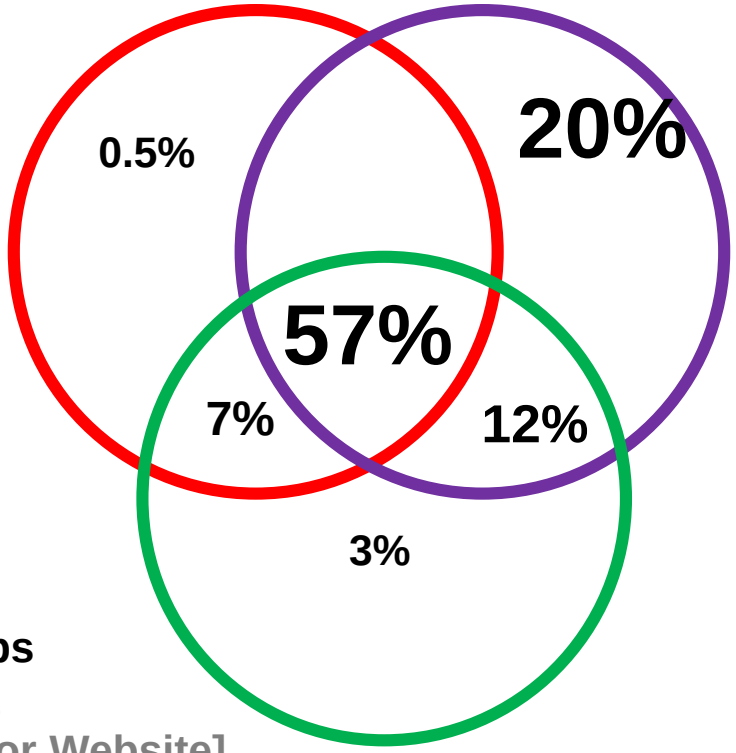
Quiz

Q1: How many transition delay faults in this circuit?
A:

Q2: Does ABC=001→011 detects B STR fault?
A:



Experimental Results



Portion of failing chips Covered by each test
[modified from Mentor Website]

No One Can Replace Each Other

Summary

- Delay fault important for advanced technologies
- Two popular delay fault models
  - Path delay fault (PDF): two faults per path
    - Rising, falling
  - Transition delay fault (TDF): two faults per node
    - STR, STF

	Path Delay Fault	Transition Delay Fault
Number of faults	☹ WC exponential	☺ linear
Fault size and distribution	☺ small fault size ☺ distributed	☹ large fault size only ☹ lumped

FFT

- **Q: Give an example circuit where number of paths is exponential to number of gates**

	Path Delay Fault	Transition Delay Fault
Number of faults	☹ **WC exponential**	☺ **linear**
Fault size and distribution	☺ **small fault size** ☺ **distributed**	☹ **large fault size** ☹ **lumped**